

**AUTOMOTIVE MOSFET**

**IRLL024NQ**

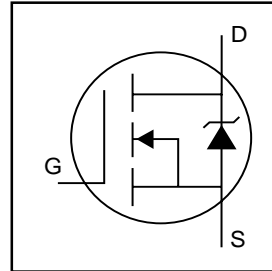
HEXFET® Power MOSFET

**Typical Applications**

- Electronic Fuel Injection
- Active Suspension
- Power Doors, Windows & Seats
- Cruise Control
- Air Bags

**Benefits**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Repetitive Avalanche Allowed up to Tjmax
- Dynamic dv/dt Rating
- Automotive [Q101] Qualified



$V_{DSS} = 55V$
$R_{DS(on)} = 0.065\Omega$
$I_D = 3.1A$

**Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET in a SOT-223 package utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this Automotive qualified HEXFET Power MOSFET are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



The efficient SOT-223 package is designed for surface mount and the enlarged tab provides improved thermal characteristics making it ideal in a variety of power applications. Power dissipation of 1.0W is possible in a typical surface mount application. Available in Tape & Reel.

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V$	3.1	A
$I_D @ T_C = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V$	2.6	
$I_{DM}$	Pulsed Drain Current ①	12	
$P_D @ T_C = 25^\circ C$	Power Dissipation ②	1.3	W
	Linear Derating Factor	8.3	mW/°C
$V_{GS}$	Gate-to-Source Voltage	±16	V
$E_{AS}$	Single Pulse Avalanche Energy ④	87	mJ
$I_{AR}$	Avalanche Current ①	See Fig.16c, 16d, 19, 20	A
$E_{AR}$	Repetitive Avalanche Energy ⑥		mJ
dv/dt	Peak Diode Recovery dv/dt ⑤	9.9	V/ns
$T_J, T_{STG}$	Junction and Storage Temperature Range	-55 to + 175	°C

**Thermal Resistance**

	Parameter	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Amb. (PCB Mount, steady state)*	90	120	°C/W
$R_{\theta JA}$	Junction-to-Amb. (PCB Mount, steady state)**	50	60	

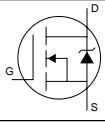
\* When mounted on FR-4 board using minimum recommended footprint.

\*\* When mounted on 1 inch square copper board, for comparison with other SMD devices.

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

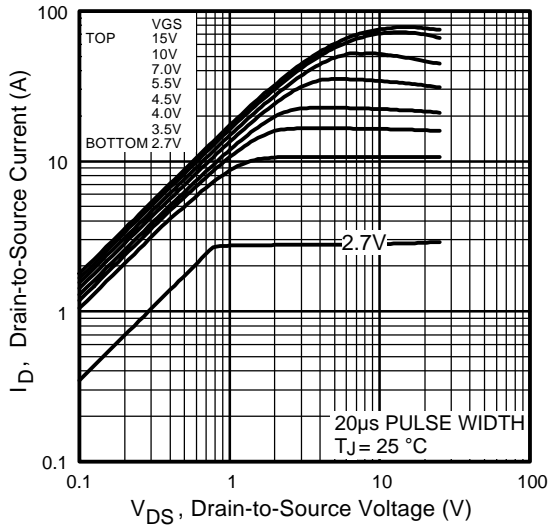
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.057	—	V/°C	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.065	mΩ	$V_{GS} = 10V, I_D = 3.1A$ ②
		—	—	0.080		$V_{GS} = 5.0V, I_D = 2.5A$ ②
$V_{GS(th)}$	Gate Threshold Voltage	1.0	—	2.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$g_{fs}$	Forward Transconductance	4.5	—	—	S	$V_{DS} = 25V, I_D = 1.9A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	25	μA	$V_{DS} = 55V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 44V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 16V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -16V$
$Q_g$	Total Gate Charge	—	11	17	nC	$I_D = 1.9A$
$Q_{gs}$	Gate-to-Source Charge	—	1.9	—		$V_{DS} = 44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	4.3	—		$V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time	—	12	—	ns	$V_{DD} = 28V$ ②
$t_r$	Rise Time	—	41	—		$I_D = 1.9A$
$t_{d(off)}$	Turn-Off Delay Time	—	48	—		$R_G = 24\Omega$
$t_f$	Fall Time	—	39	—		$R_D = 15\Omega$
$C_{iss}$	Input Capacitance	—	508	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	141	—		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	62	—		$f = 1.0MHz$

## Source-Drain Ratings and Characteristics

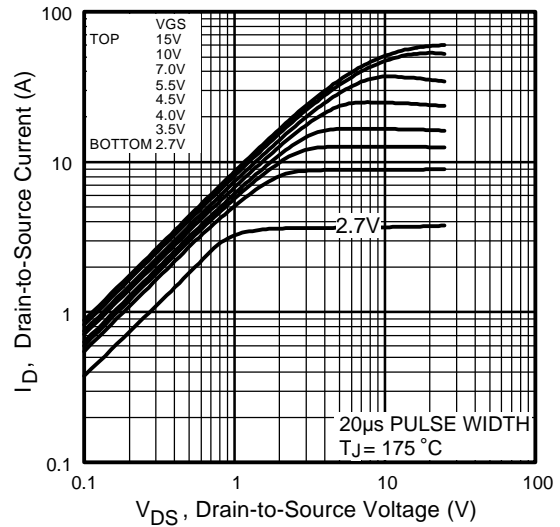
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	3.1	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	12		
$V_{SD}$	Diode Forward Voltage	—	—	1.0	V	$T_J = 25^\circ\text{C}, I_S = 1.9A, V_{GS} = 0V$ ②
$t_{rr}$	Reverse Recovery Time	—	40	60	ns	$T_J = 25^\circ\text{C}, I_F = 1.9A$
$Q_{rr}$	Reverse Recovery Charge	—	65	97	nC	$di/dt = 100A/\mu s$ ②

### Notes:

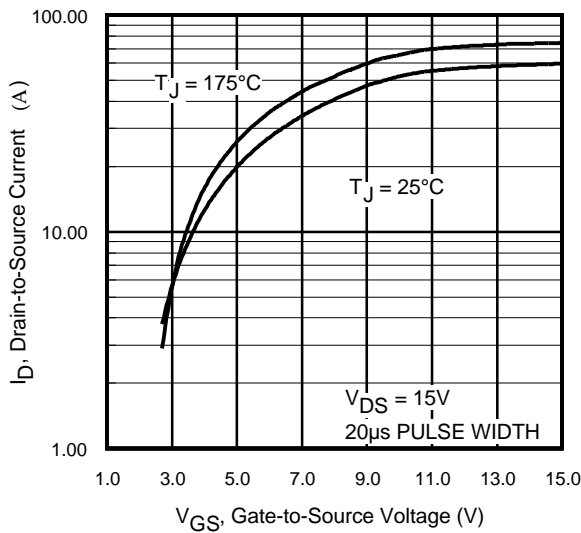
- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .
- ③ Surface mounted on 1 in square Cu board
- ④ Starting  $T_J = 25^\circ\text{C}$ ,  $L = 18mH$   
 $R_G = 25\Omega, I_{AS} = 3.1A$ . (See Figure 12).
- ⑤  $I_{SD} \leq 1.9A, di/dt \leq 197A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175^\circ\text{C}$
- ⑥ Limited by  $T_{Jmax}$ , see Fig.16c, 16d, 19, 20 for typical repetitive avalanche performance.



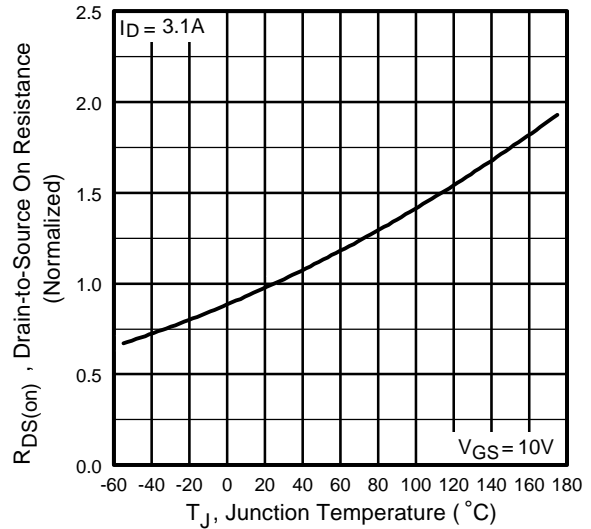
**Fig 1.** Typical Output Characteristics



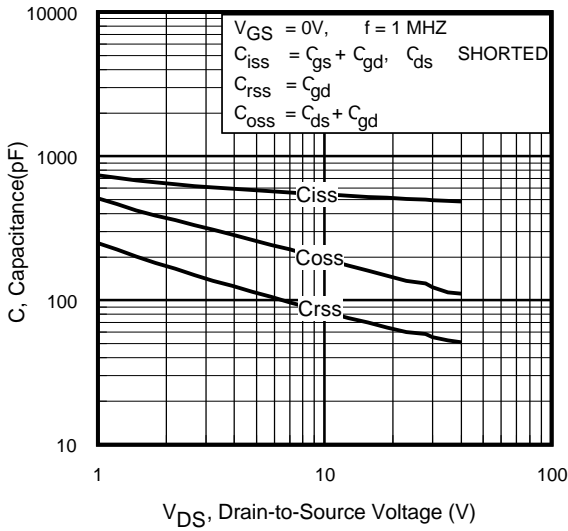
**Fig 2.** Typical Output Characteristics



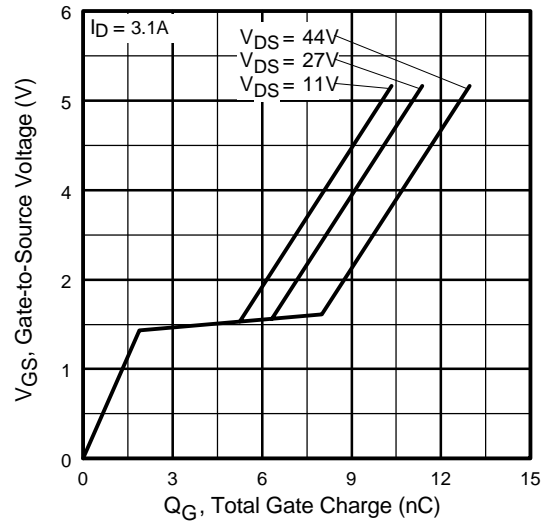
**Fig 3.** Typical Transfer Characteristics



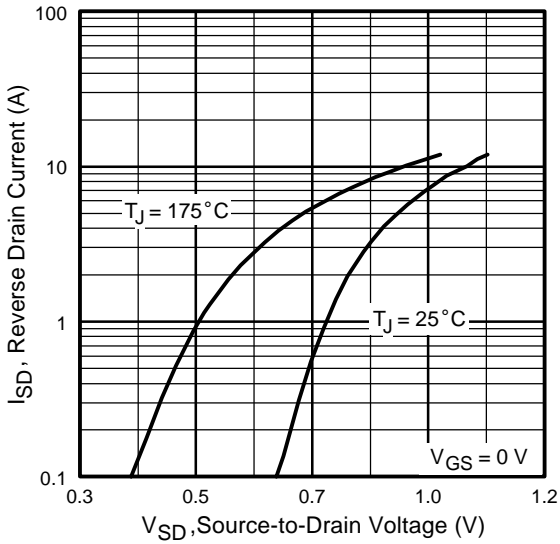
**Fig 4.** Normalized On-Resistance Vs. Temperature



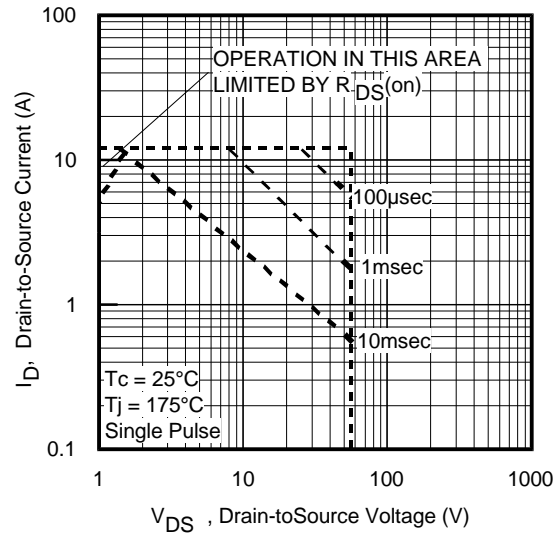
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



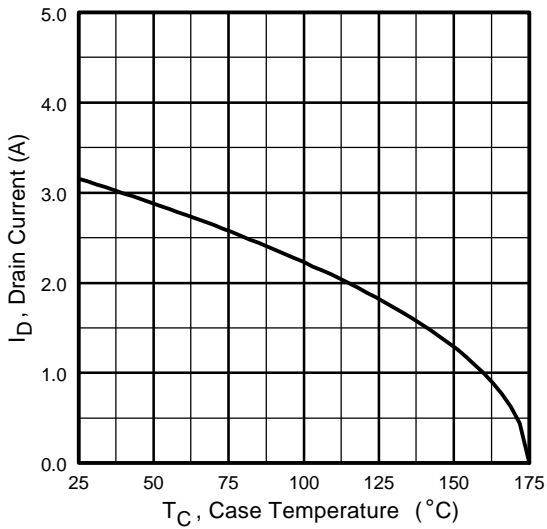
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



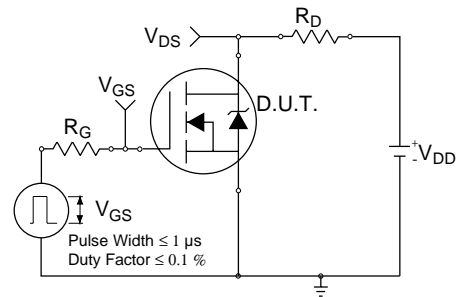
**Fig 7.** Typical Source-Drain Diode Forward Voltage



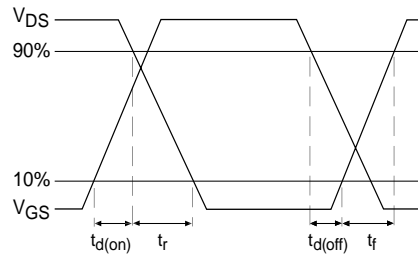
**Fig 8.** Maximum Safe Operating Area



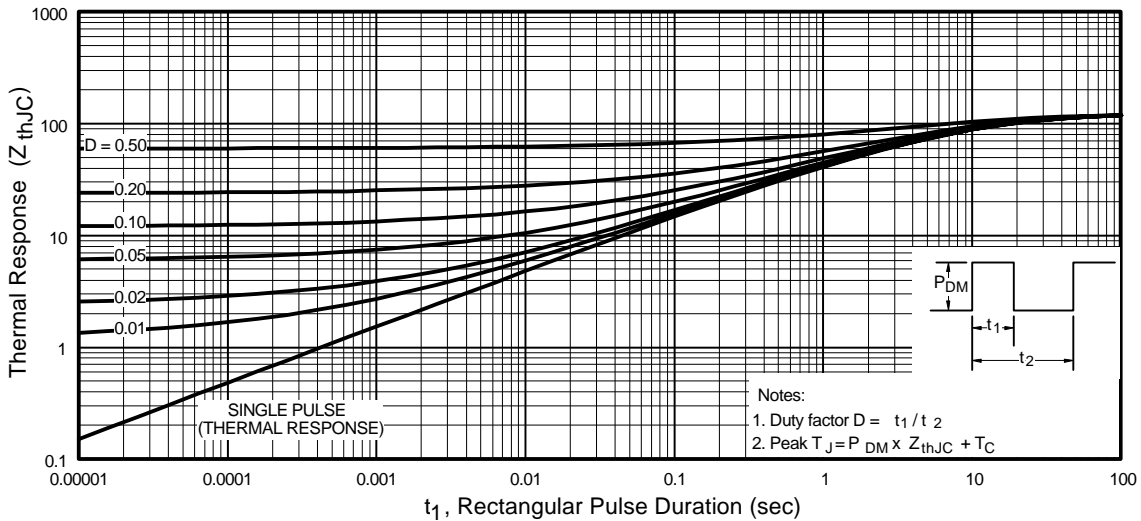
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit

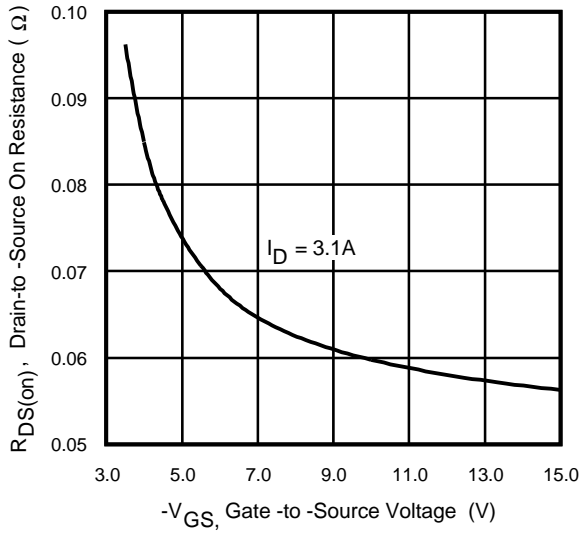


**Fig 10b.** Switching Time Waveforms

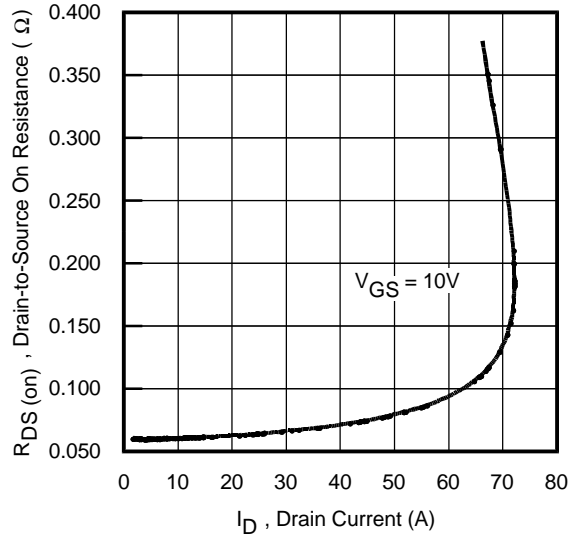


**Fig 11.** Typical Effective Transient Thermal Impedance, Junction-to-Ambient

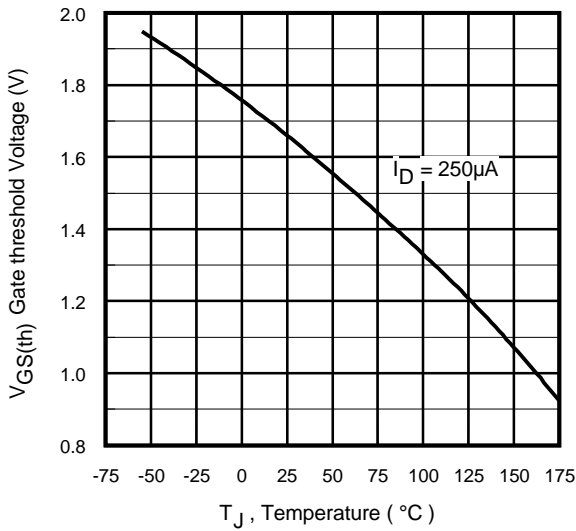
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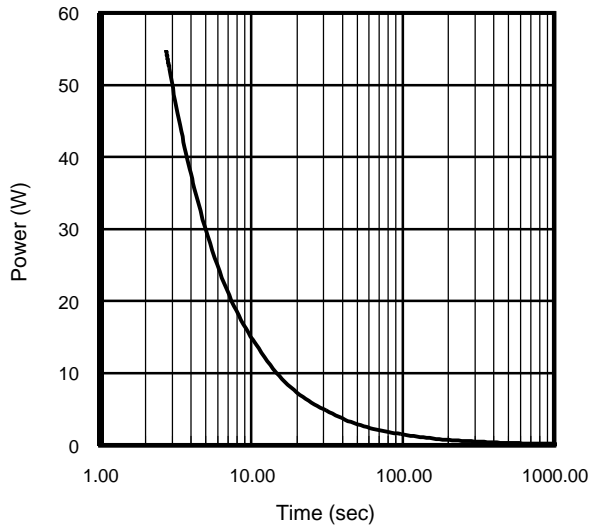
**Fig 12.** Typical On-Resistance Vs. Gate Voltage



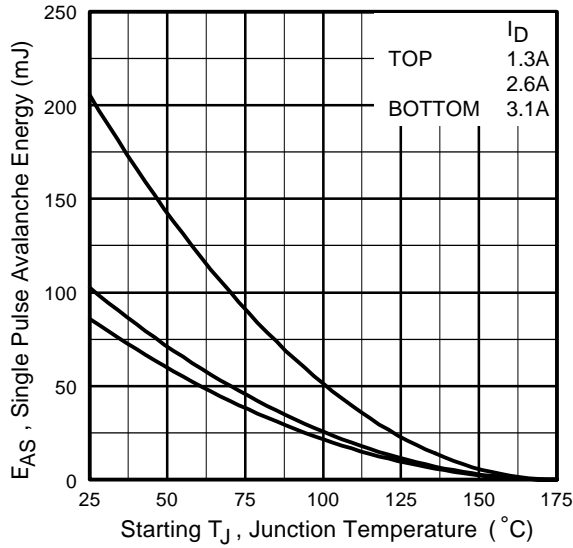
**Fig 13.** Typical On-Resistance Vs. Drain Current



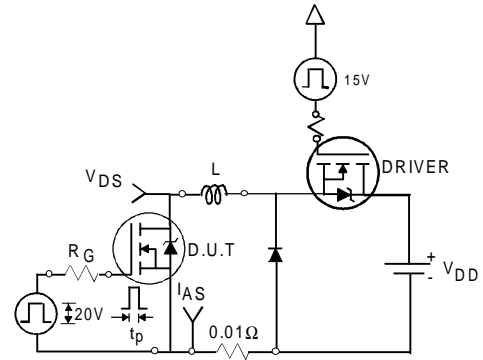
**Fig 14.** Typical Threshold Voltage Vs. Junction Temperature



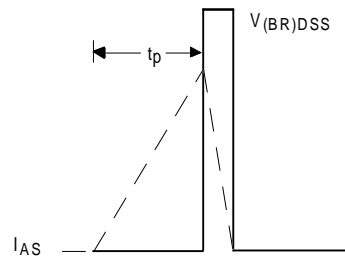
**Fig 15.** Typical Power Vs. Time



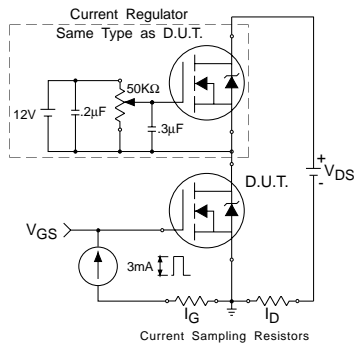
**Fig 16a.** Maximum Avalanche Energy Vs. Drain Current



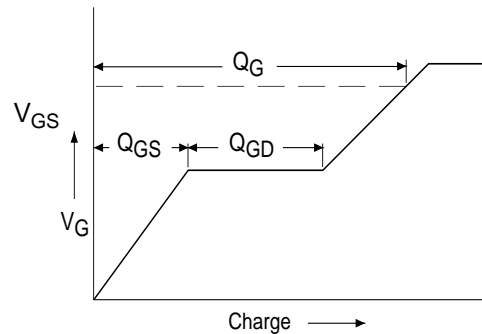
**Fig 16c.** Unclamped Inductive Test Circuit



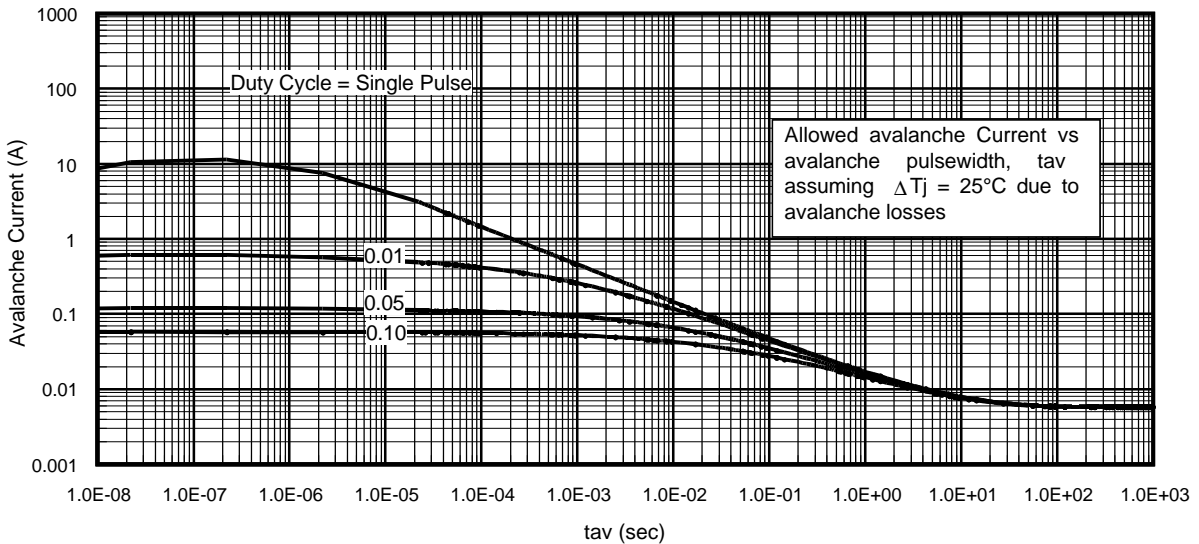
**Fig 16d.** Unclamped Inductive Waveforms



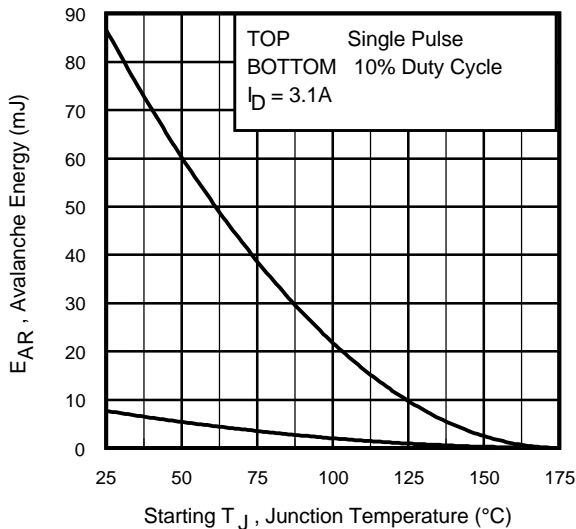
**Fig 17.** Gate Charge Test Circuit



**Fig 18.** Basic Gate Charge Waveform



**Fig 19.** Typical Avalanche Current Vs.Pulswidth



**Fig 20.** Maximum Avalanche Energy Vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 15, 16:**  
(For further info, see AN-1005 at [www.irf.com](http://www.irf.com))

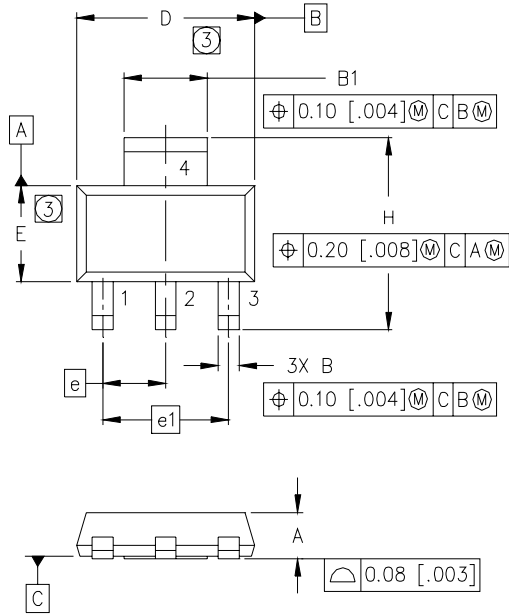
1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^\circ\text{C}$  in Figure 15, 16).  
 $t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$P_{D(ave)} = 1/2 ( 1.3 \cdot BV \cdot I_{av} ) = \Delta T / Z_{thJC}$$

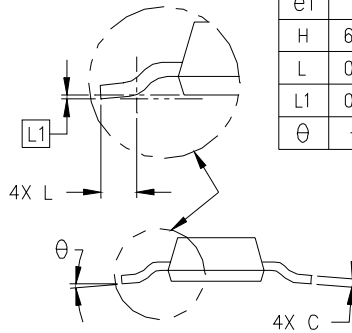
$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

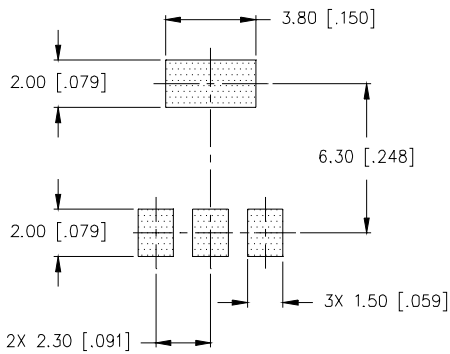




DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.55	1.80	.061	.071
B	0.65	0.85	.026	.033
B1	2.95	3.15	.116	.124
C	0.25	0.35	.010	.014
D	6.30	6.70	.248	.264
E	3.30	3.70	.130	.146
e	2.30	BSC	.0905	BSC
e1	4.60	BSC	.181	BSC
H	6.71	7.29	.264	.287
L	0.91	—	.036	—
L1	0.061	BSC	.0024	BSC
θ	—	10°	—	10°



MINIMUM RECOMMENDED FOOTPRINT



LEAD ASSIGNMENTS

- 1 = GATE
- 2 = DRAIN
- 3 = SOURCE
- 4 = DRAIN

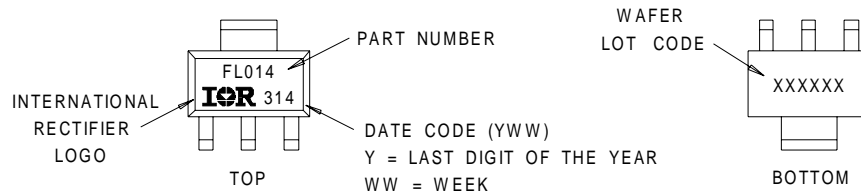
NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS DO NOT INCLUDE MOLD FLASH.
4. OUTLINE CONFORMS TO JEDEC OUTLINE TO-261AA.
5. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

## Part Marking Information

SOT-223

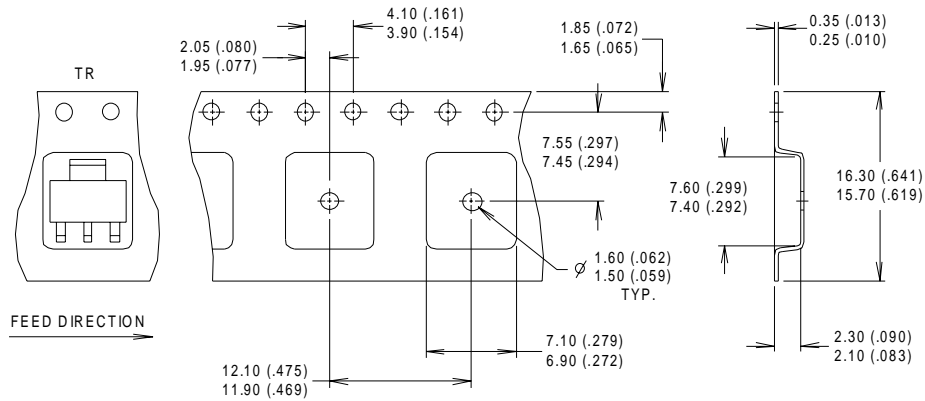
EXAMPLE: THIS IS AN IRFL014



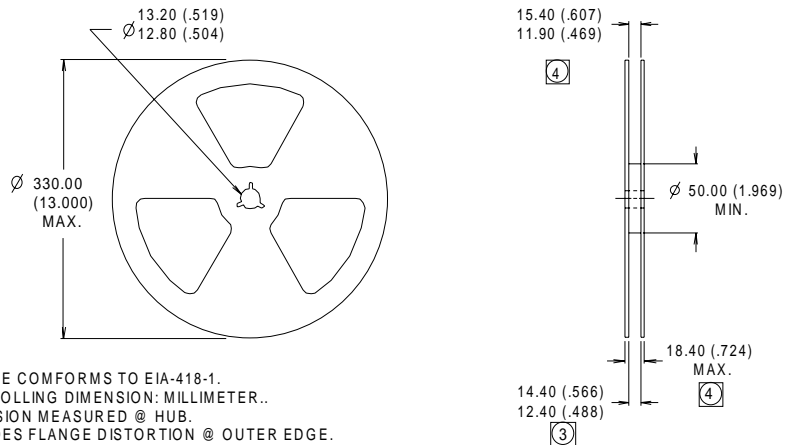
# IRLL024NQ

International  
**IR** Rectifier

## Tape & Reel Information SOT-223



- NOTES :
1. CONTROLLING DIMENSION: MILLIMETER.
  2. OUTLINE CONFORMS TO EIA-481 & EIA-541.
  3. EACH  $\varnothing 330.00$  (13.00) REEL CONTAINS 2,500 DEVICES.



- NOTES :
1. OUTLINE COMFORMS TO EIA-418-1.
  2. CONTROLLING DIMENSION: MILLIMETER..
  - ③ DIMENSION MEASURED @ HUB.
  - ④ INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Automotive [Q101] market.  
Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

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